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Outline

- What are thermoelectrics?
- NASA's uses
- Life time performance criteria
- The irradiation
- Research method and data
 - Resistivity
 - Thermal Conductivity
- Conclusion

What are Thermoelectrics(TE)?

- Conversion of heat into electric energy.
- Done based on the Seebeck Effect.
- Temperature differential causes electrons to diffuse to the cold side. (Potential barrier that arises to prevent diffusion is the Seebeck voltage.)
- The connection of p- and n-type elements creates a power device.



Conversion efficiency is function of ZT and ΔT



- T = Temperature
- ρ = resistivity
- k= Thermal conductivity
- All of which are testable in the lab

Why use thermoelectrics to power spacecrafts?



NASA's deep space and planetary missions –Where solar power is not available or not practical. Compact, solid-state

- devices
 - -Survives the vibrations from launch.
 - -No vibration or electromagnetic interference for sensitive instrumentation.
- Long lifetimes

-Voyager over 30 years



Current NASA Missions

• The thermoelectric power systems used are called Radioisotope Thermoelectric Generators (RTGs) which power deep space probes and rovers.





Cassini - Saturn

Mars Science Laboratory

http://saturn.jpl.nasa.gov/;

http://marsprogram.jpl.nasa.gov/msl/

Hot Side?

- The hot side of RTG's is typically kept at temperatures around 1275K. How???
- Through alpha decay based heat sources.
- Pu-238 is the heat source used.











 Under ATEC project, high-temperature TE materials are under development for integration into Radioisotope Thermoelectric Generators (RTGs) at the Jet Propulsion Laboratory (JPL).



Demonstrating Life-time of New TE Technology for use in RTGs.

- Determine potential problems which could lead to the degradation of RTG's power supply over time:
 - Sublimation of materials
 - Breakdown of interfacial electrical contact resistance
 - Degradation of thermoelectric properties
 - Mechanical behavior

Potential impact of irradiation on thermoelectric materials!

Possible Performance Degradation through Irradiation

- Undesired contaminating Pu-240 in Pu-238 may cause a degree of fission neutron radiation over time.
- Fission neutrons in the energy range of 100KeV to 8MeV could cause lattice damage in TE materials.
 - Some of this damage may be annealed in real time during operation.
- Any change in the lattice structure may effect the TE properties of the materials used.
 - This would decrease the performance of RTG's over time.



Skutterudites Lattice



Zintl Phases Lattice





Simulated Irradiation

- The below samples were exposed to 17 years worth of neutron radiation in 35 minutes. This was done near room temperature at the Ohio State University Research Reactor (OSURR).
 - 3 Samples: n-type La_{3-x}Te₄
 - 3 Samples: p-type Yb₁₄MnSb₁₁ (Zintl)
 - 3 Samples: n-type filled skutterudites
 - 3 Samples: p-type filled skutterudites





Samples separated Inside the ampoule By quartz separators



Measurements

- The TE properties of the materials were tested at two different stages
 - Pre-irradiation at room temperature (RT)
 - Post-irradiation RT and high temperature (HT) measurements.
- The properties tested were:
 - Electrical resistivity (ρ)
 - Thermal conductivity (K)
 - Seebeck coefficient (α) (pending)

 $\frac{\alpha^2 T}{\rho k}$ zT



Seebeck change was all under 10%

- Within margin of error for RT Seebeck

RT Resistivity



Resistivity change was within 5% Within margin of error for RT Hall measurements <u>RT Electrical resistivi</u>ty did not degrade!



Thermal Conductivity (TC) Measurements

Post-Irradiation Thermal Conductivity was compared to pre-irradiation average - Avg. has 12% spread.

All TC data measured post irradiation was within the spread of the preirradiation data, as well as within measurement error.



n-SDKT 1 TC

n-SKDT 2 TC

n-SDKT 3 TC

Avg. n-SKDT TC





Resistivity (mOhm*cm)

- Sample 1 and 3 fell within the spread of the pre-irradiation data - Sample 2 was just beyond it. Accounting for error on each individual measurement Sample 2 may still fall within spread.

LaTe followed the Pre-Irradiation curve almost exactly. - No HT degredation.





Analysis

- n-Skutterudite, p-Skutterudite, and LaTe post-irradiation resistivity and thermal conductivity all were within the margin of error or spread of pre-irradiation measurements.
- Due to contamination in the original Zintl sample batch, the behavior of post-irradiated data was skewed.

Conclusion

- No explicit radiation damage could be measured in TE properties of n- and p-Skutterudites.
 - Pending Seebeck measurements
- LaTe: Displayed no noticeable change in TE properties.
- Zintl: May have been influenced from the neutron irradiation, but original sample batch was contaminated, thus new samples need to be created and tested.
- Overall it seems these materials will be able to resist degradation to any neutron radiation.

Further research:

- HT Seebeck should still be recorded for all of the samples.
- Zintl had contaminates in the original sample and needs to be remade.

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